



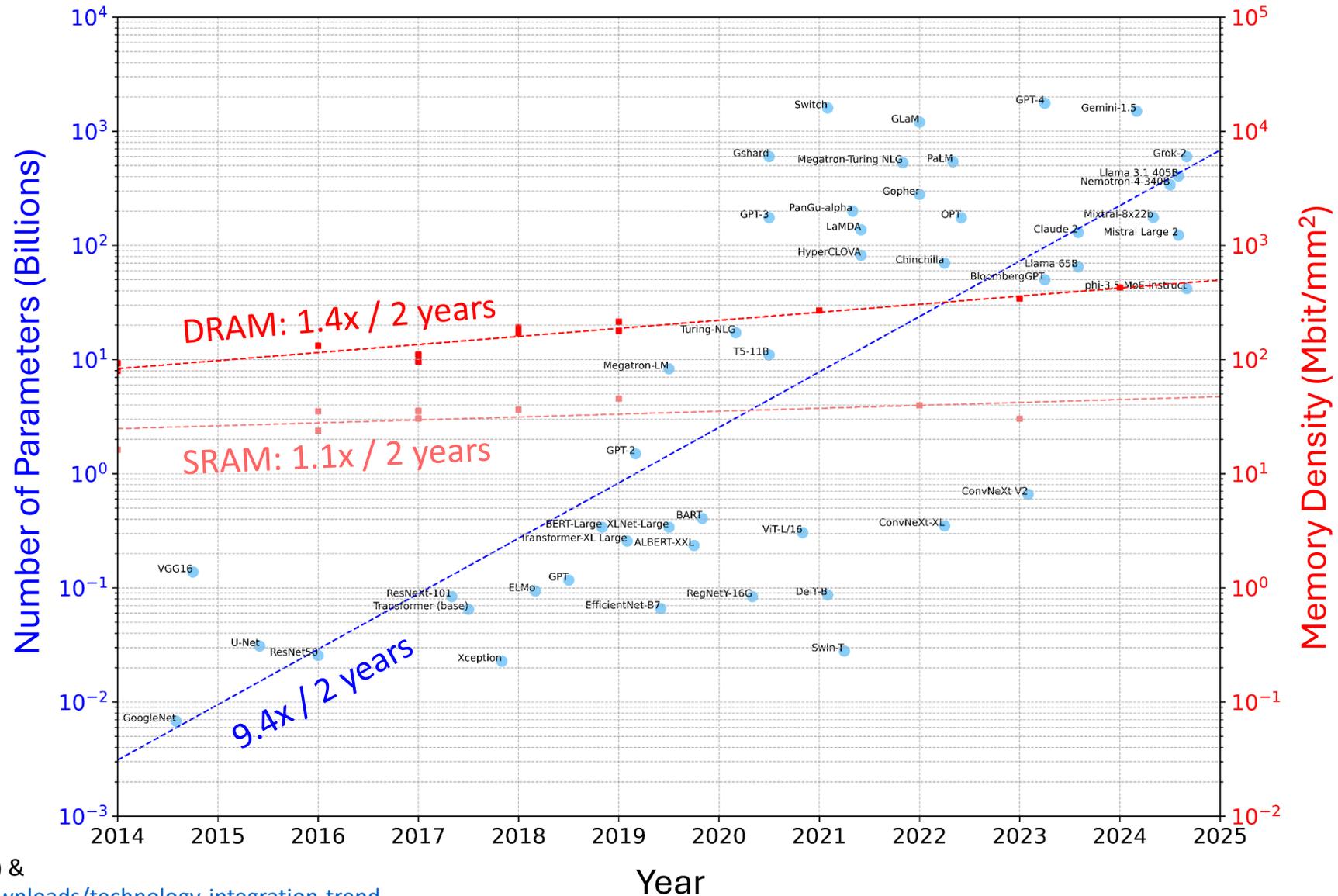
Future of Memory: **Massive, Diverse,** **Tightly Integrated** with Compute – from Device to Software

Shuhan Liu^{1*}, Robert M. Radway¹, Xinxin Wang¹, Jimin Kwon¹,
Caroline Trippel², Philip Levis², Subhasish Mitra^{1,2}, H.-S. Philip Wong^{1*}

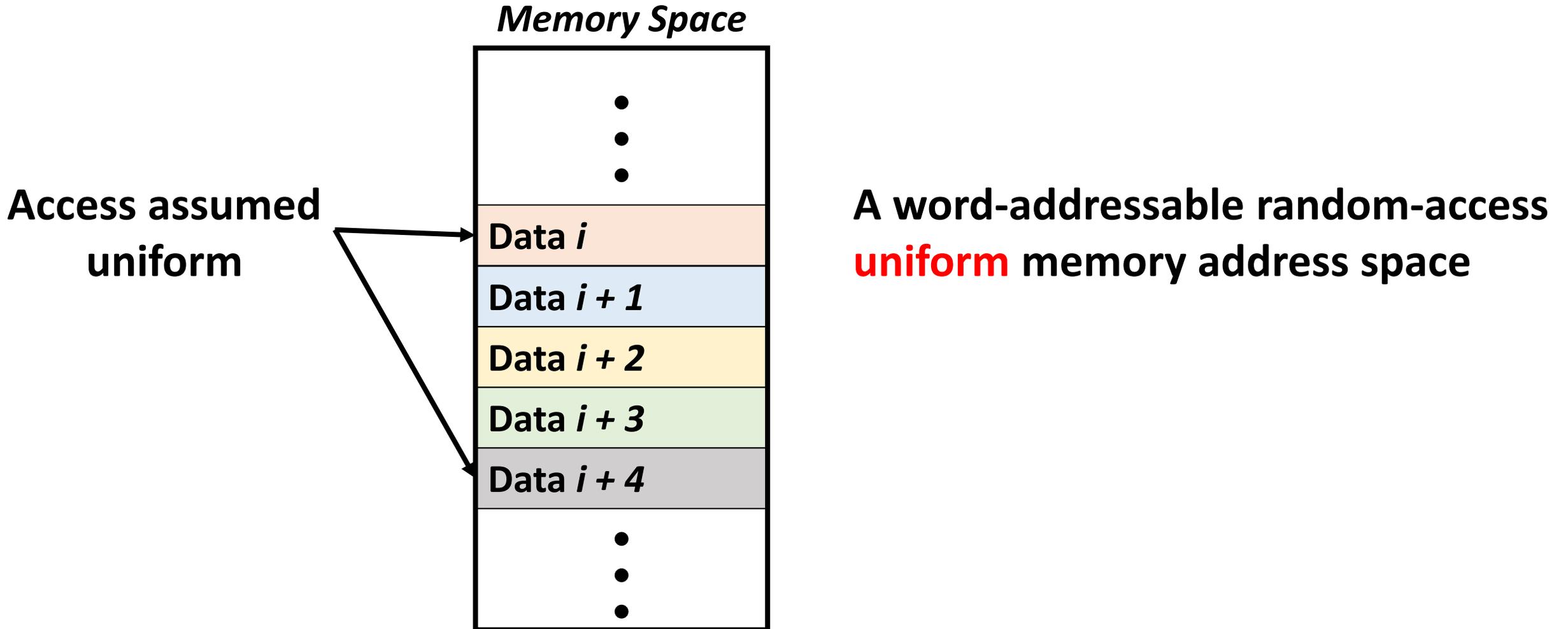
¹Department of EE, ²Department of CS, Stanford University, CA, USA.

(*E-mail: shliu98@stanford.edu, hspwong@stanford.edu)

Memory Needs Outpace Memory Advances



Software Assumes Uniform Memory



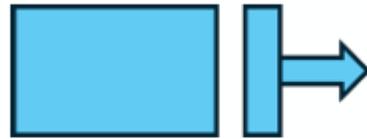
Software Use of Memory: Very Diverse



Data Analytics

Streams of data

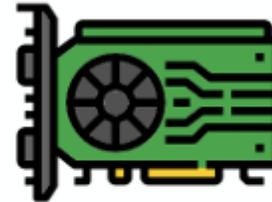
- Write-once, read-once
- Filters (scans)
- Joins (random access)



Append-Mostly
Databases

Read >> Write

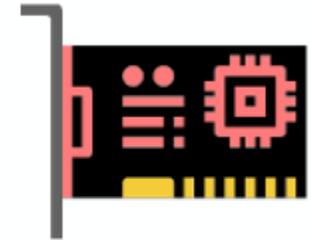
- Write once
- Mostly append
- Read many times
- Scans
- Random access



Machine Learning
Accelerator

Blocked operations

- Blocked operations
- Sparse accesses
- Read multiple times
- Write many times



High-Speed
Networking

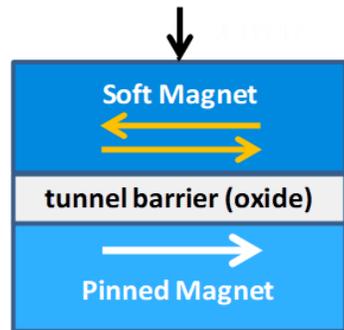
Packet-oriented

- Ultra-low latency
- Header processing
- Packet-oriented
- Read once
- Write once

Philip Levis, Differentiated Memory (DAM) Project white paper,
<https://dam.stanford.edu/>

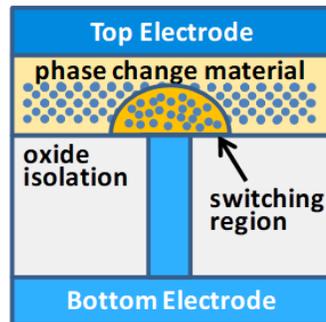
Diverse Memories

Various parts of this memory have to perform functions which differ somewhat in their nature and considerably in their purpose ... — J. von Neumann 1946



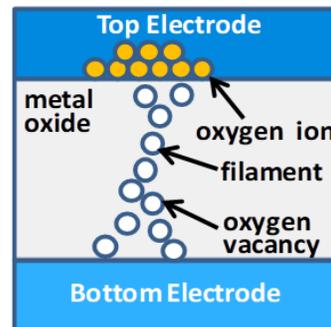
STT-MRAM

Spin transfer torque magnetic random access memory



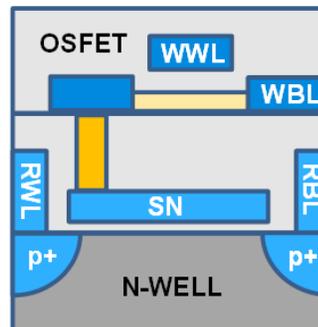
PCM

Phase change memory



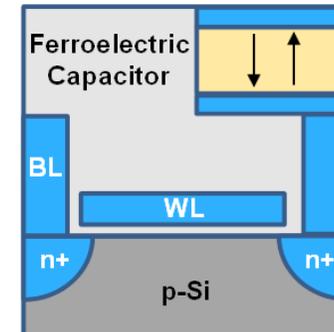
RRAM

Resistive switching random access memory



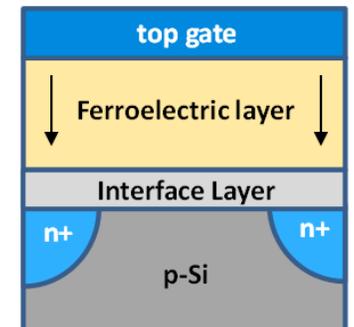
Gain Cell

Gain cell memory (quasi-non-volatile)



FeRAM

Ferro-electric 1T1C memory (destructive read)

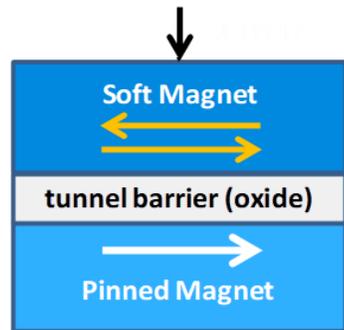


FeFET

Ferro-electric field effect transistor

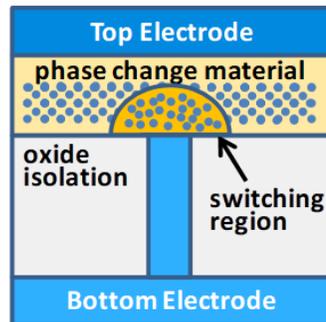
Diverse Memories

Focus on: integration of memory with new capabilities as a tool in our toolbox



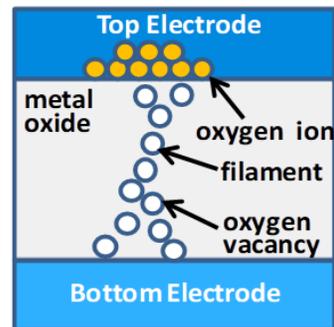
STT-MRAM

Spin transfer torque magnetic random access memory



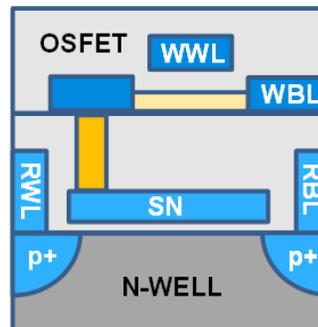
PCM

Phase change memory



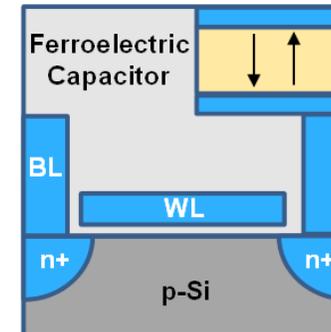
RRAM

Resistive switching random access memory



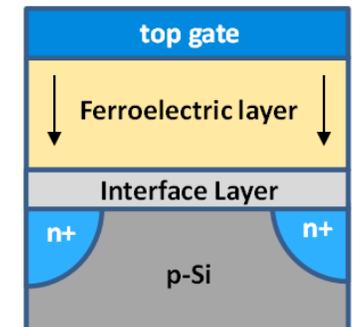
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Gain cell memory (quasi-non-volatile)



FeRAM

Ferro-electric 1T1C memory (destructive read)

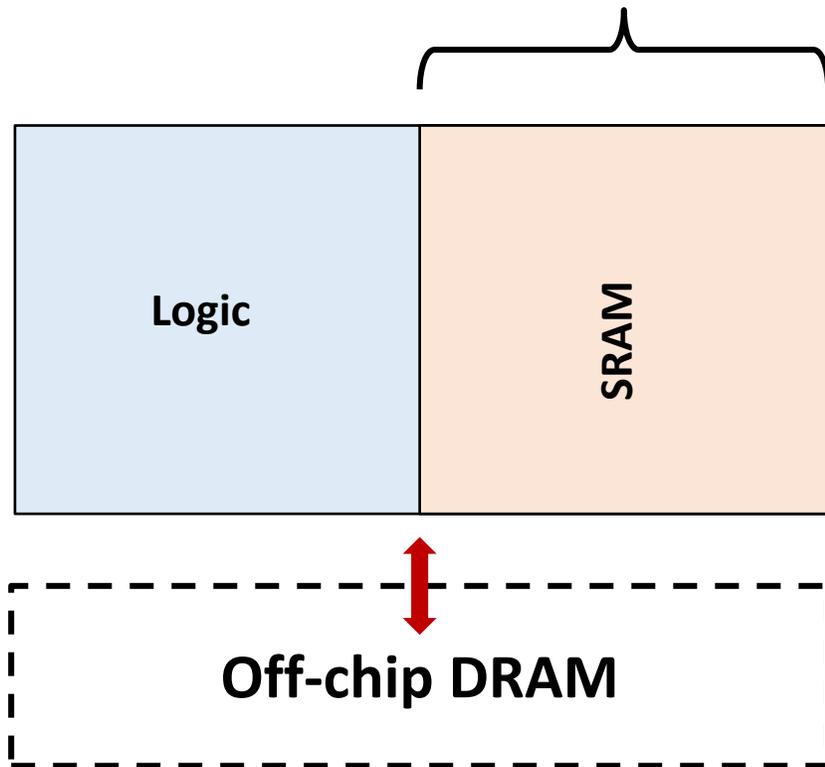


FeFET

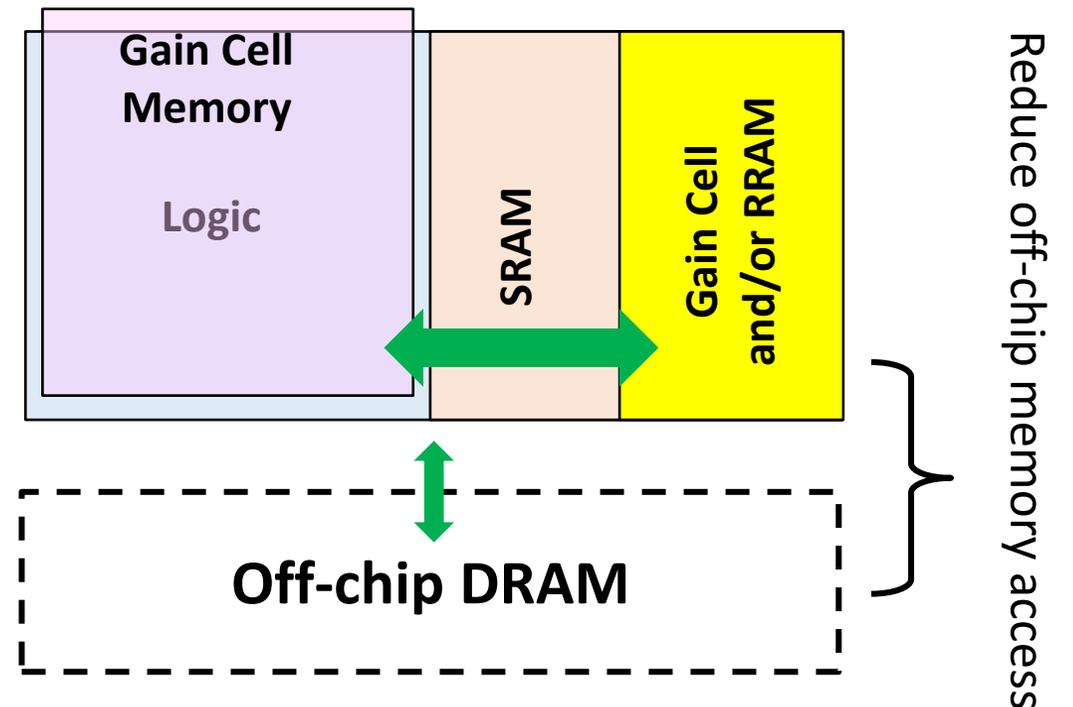
Ferro-electric field effect transistor

Massive Memory On-Chip

Capacity limited by SRAM scaling

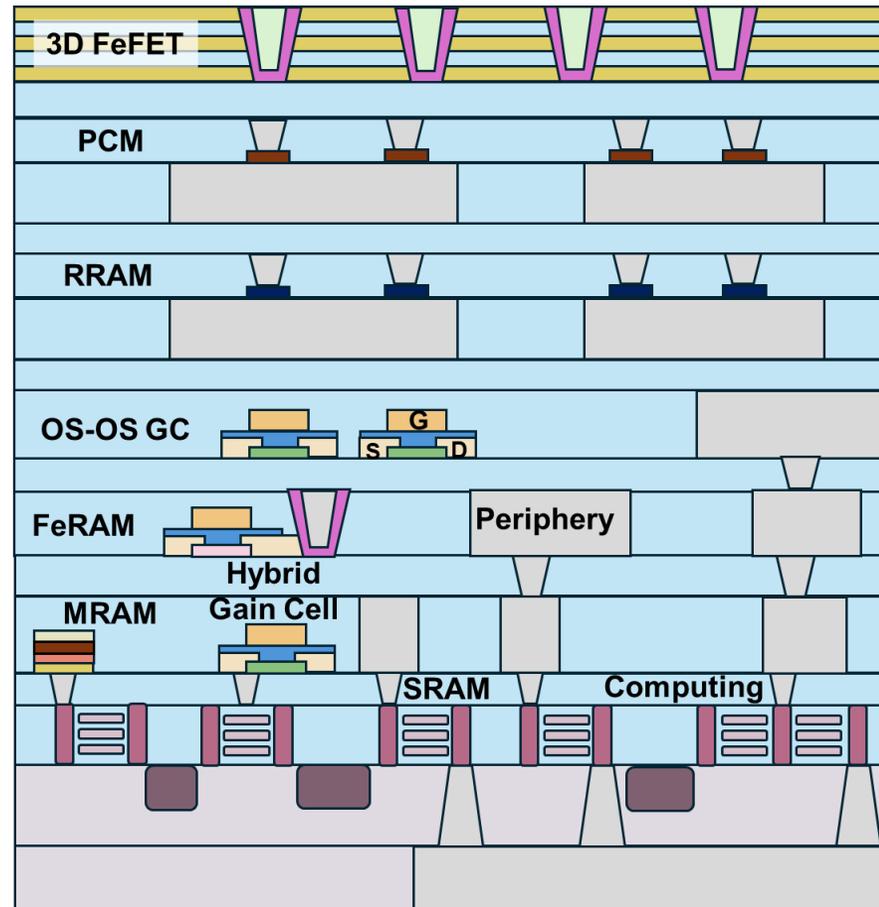


3D on top of logic



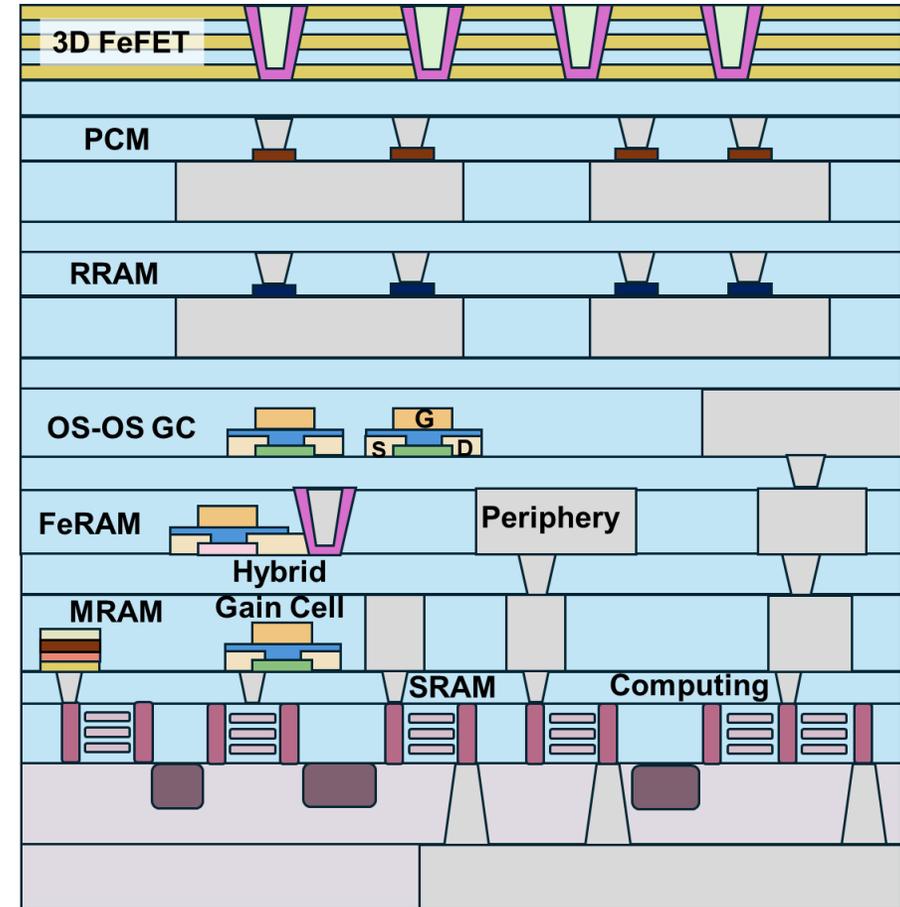
Future of Memory:

Massive, Diverse, Tightly Integrated with Compute

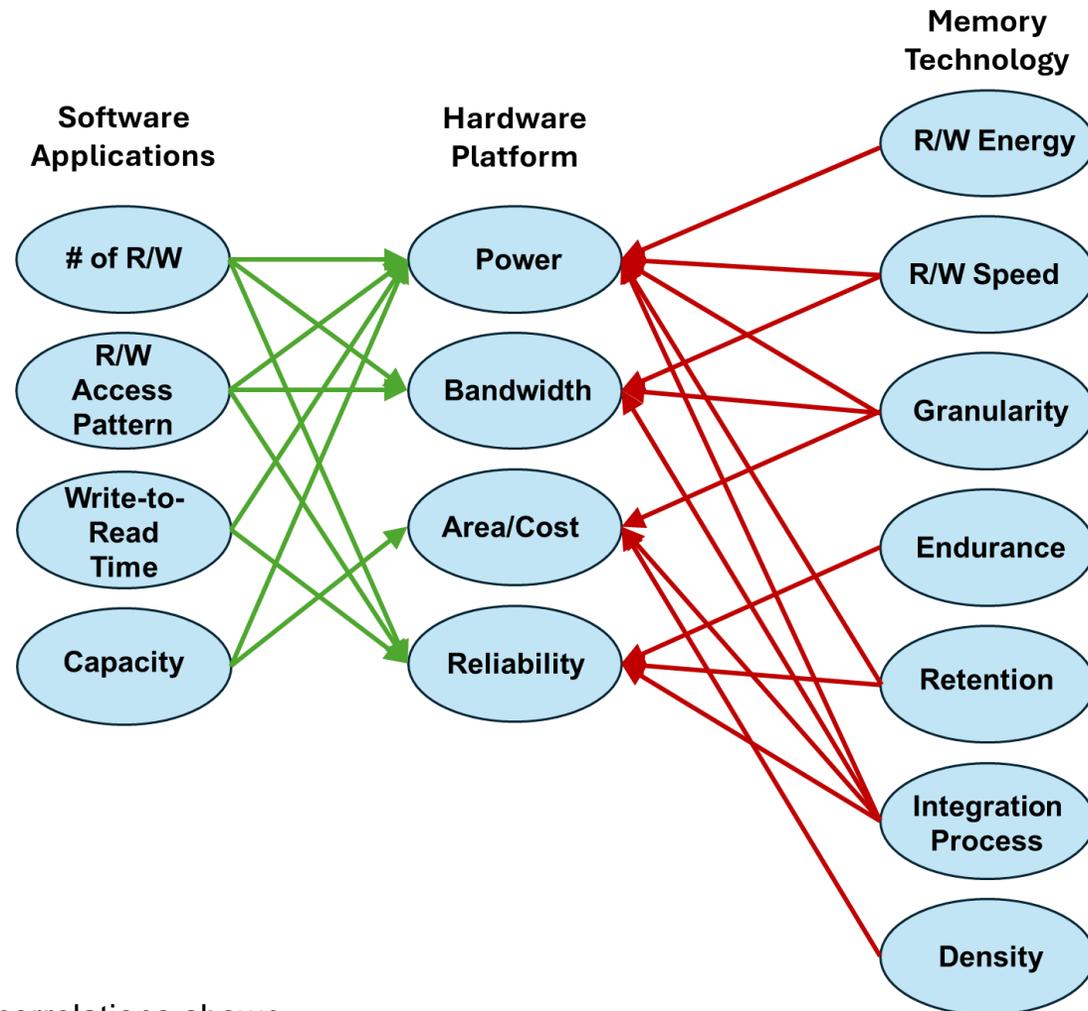


Diverse Memory:

- How to choose?
- How to use?
- What attributes are important?



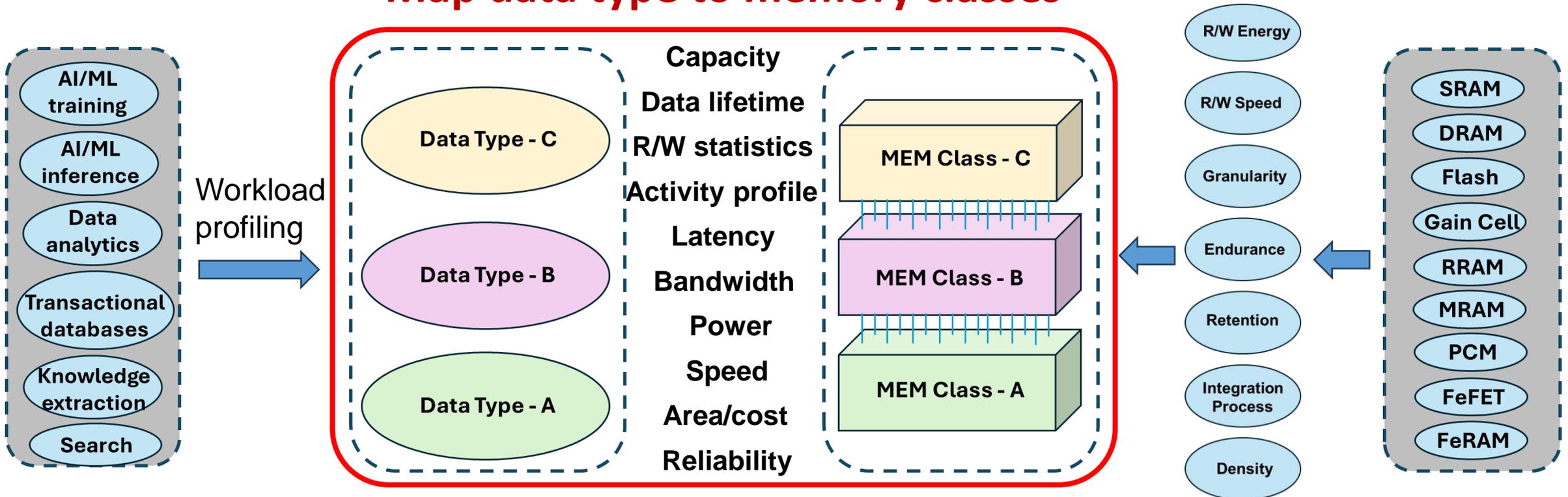
Exposing Hardware to Software



Only major direct correlations shown

Abstraction Layer Needed

Map data type to memory classes

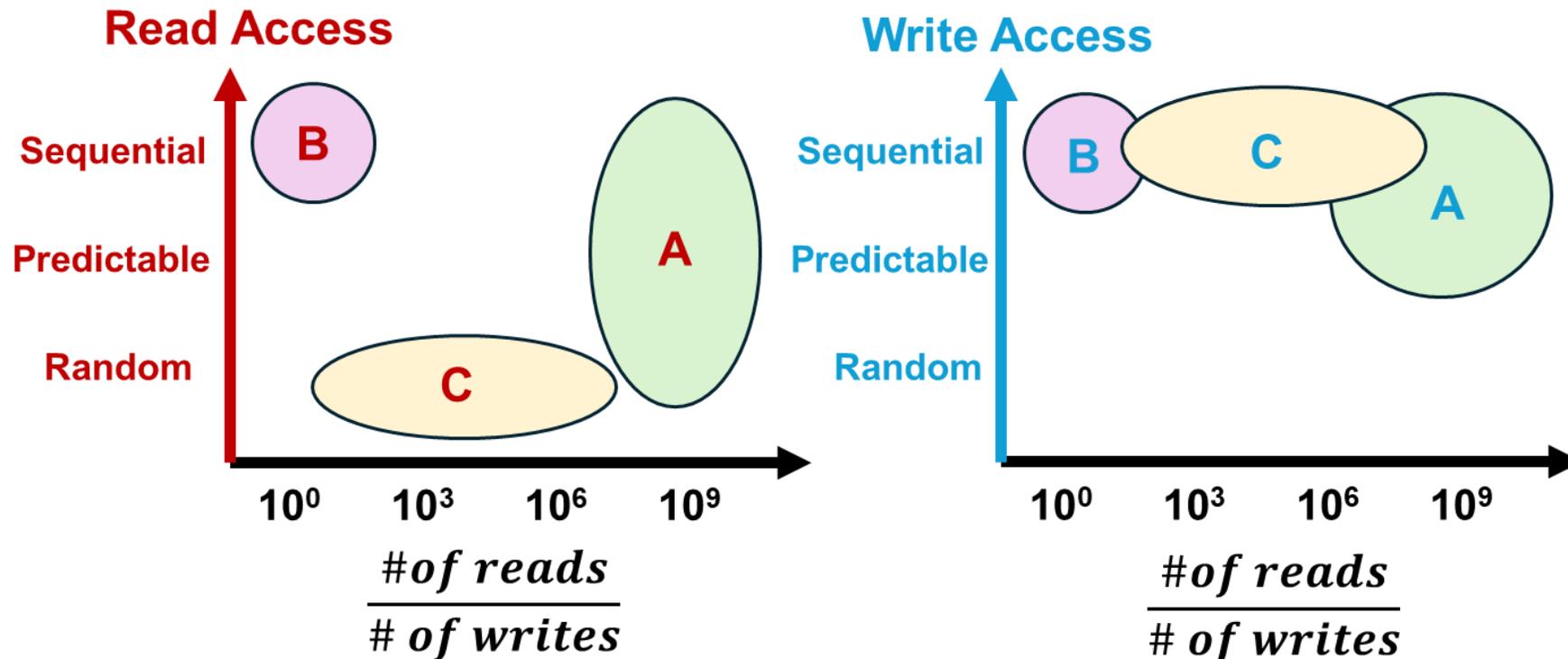


Software Data Types

Type A “mostly read” – e.g. AI/ML inference weight memory and processor instruction caches

Type B “streaming data” – e.g. streaming I/O, AI/ML activations, and data analytics

Type C “frequent write” – e.g. buffers for a file system, AI/ML training memory



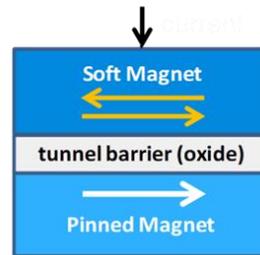
Other attributes:

- Capacity
- Data lifetime
- Access granularity
- Latency...

Type A “mostly read” – Frequent Reads, Infrequent Writes, Predictable Accesses

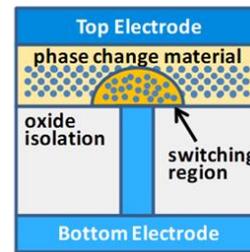
Trade-off write costs for better read

Data type	Example	Read Energy (pJ/bit)	Read Latency (ns)	Write Energy (pJ/bit)	Write Latency (ns)	Endurance (cycles)	Retention (s)	Capacity	Access granularity	Memory Today	Future Memory
A	Instruction cache	< 0.5	< 1	< 500	< 1,000	> 1 × 10 ⁸	> 1	8KB-1MB	Word (8-16B)	SRAM	MRAM, RRAM



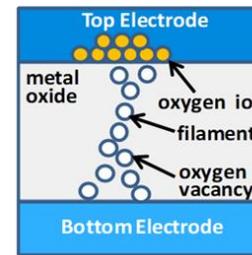
STT-MRAM

Spin transfer torque magnetic random access memory



PCM

Phase change memory



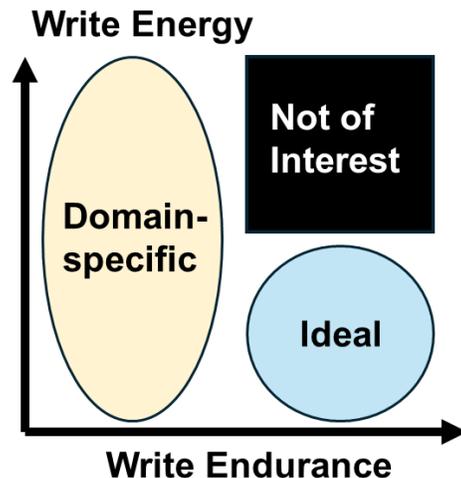
RRAM

Resistive switching random access memory

COMBINATION of Attributes Matters

Trade-off write costs for better read, **but write also matters**

Data type	Example	Read Energy (pJ/bit)	Read Latency (ns)	Write Energy (pJ/bit)	Write Latency (ns)	Endurance (cycles)	Retention (s)	Capacity	Access granularity	Memory Today	Future Memory
A	Instruction cache	< 0.5	< 1	< 500	< 1,000	$> 1 \times 10^8$	> 1	8KB-1MB	Word (8-16B)	SRAM	MRAM, RRAM

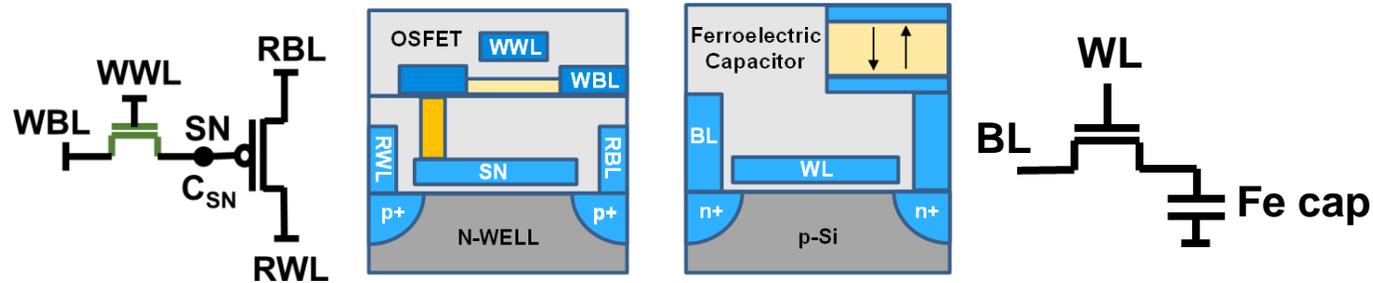


Example RRAM/MRAM :
Write energy & endurance should be optimized together

Type B “streaming data” – Frequent Writes, Few Reads per Write, Short Data Lifetime

Trade-off retention for speed/density/energy

Data type	Example	Read Energy (pJ/bit)	Read Latency (ns)	Write Energy (pJ/bit)	Write Latency (ns)	Endurance (cycles)	Retention (s)	Capacity	Access granularity	Memory Today	Future Memory
B	Video streaming	< 200	< 1,000	< 200	< 1,000	$> 1 \times 10^9$	0.1 - 10	1KB-10MB	Page (KB)	DRAM	FeRAM, Gain Cell



Gain Cell

Gain cell memory
(quasi-non-volatile)

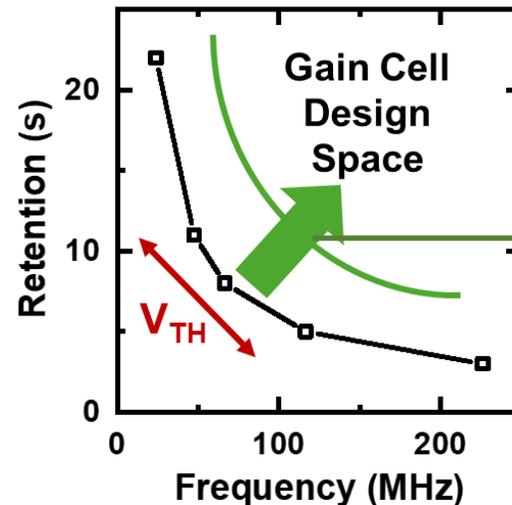
FeRAM

Ferro-electric
1T1C memory
(destructive read)

Trade-off Design Knob Matters

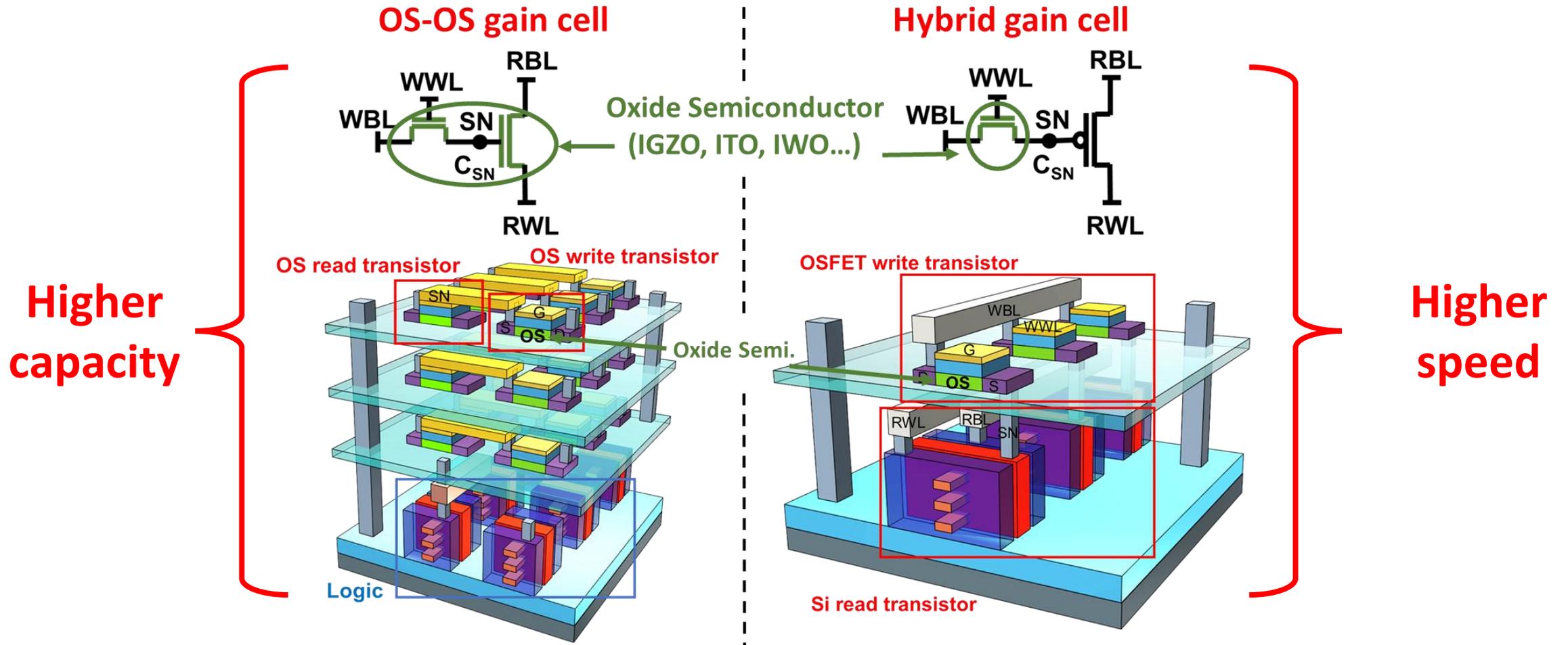
Trade-off retention for speed/density/energy

Data type	Example	Read Energy (pJ/bit)	Read Latency (ns)	Write Energy (pJ/bit)	Write Latency (ns)	Endurance (cycles)	Retention (s)	Capacity	Access granularity	Memory Today	Future Memory
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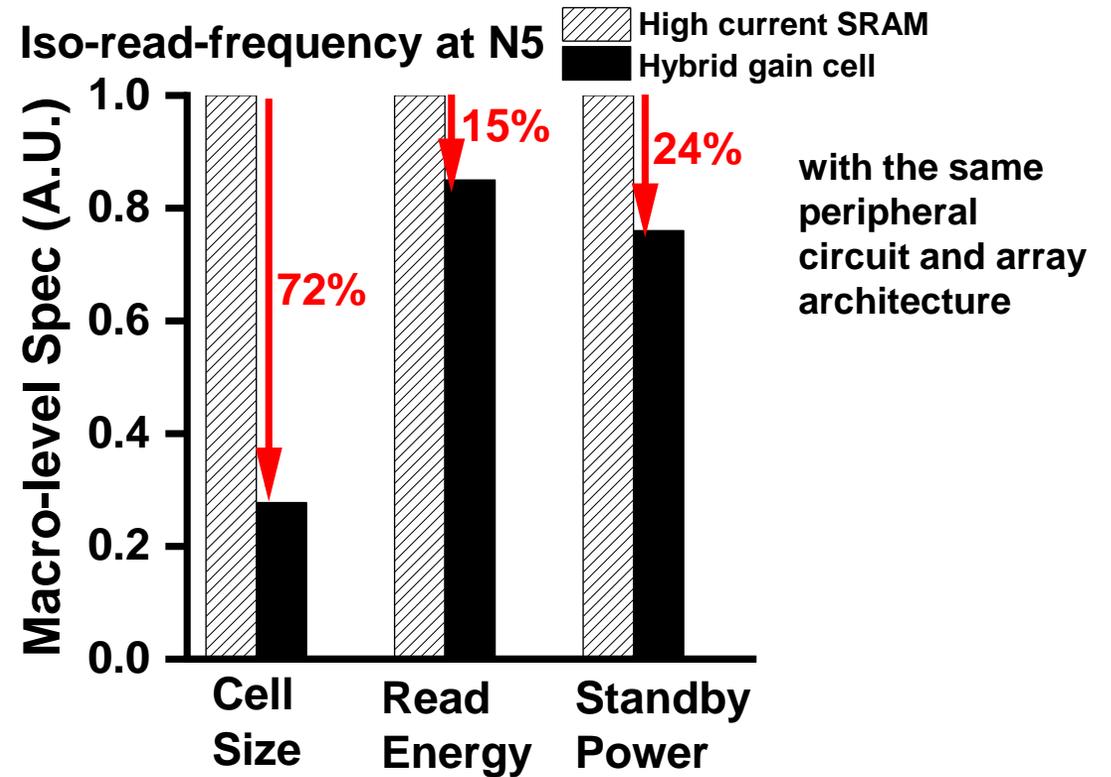
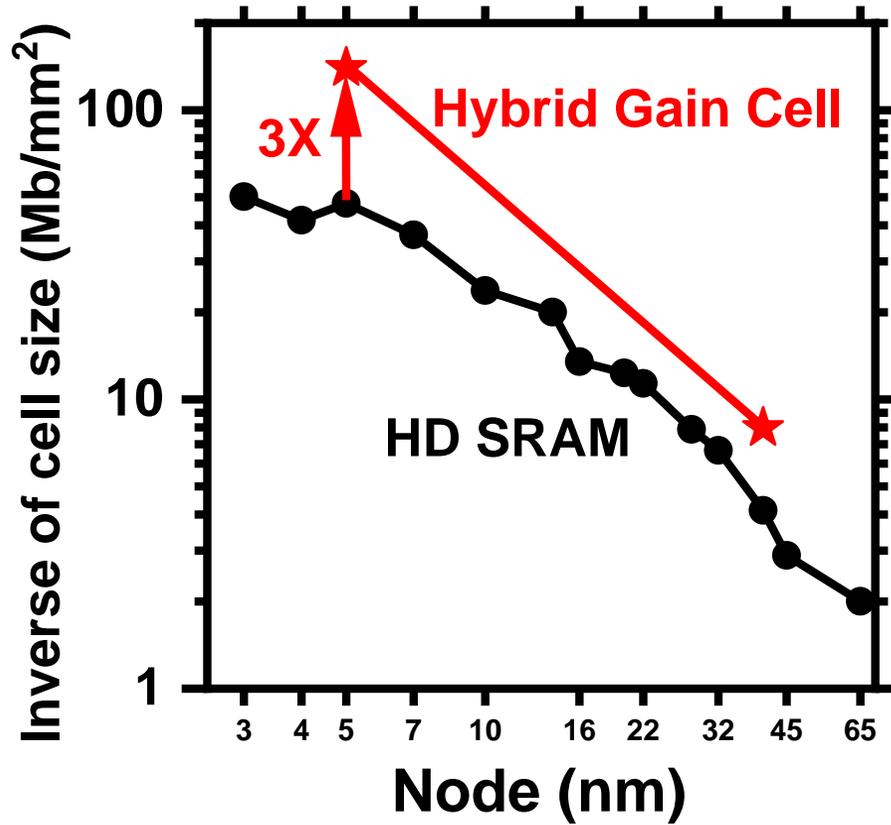


Device: SS, transition region
Circuit: voltage, hybrid gain cell

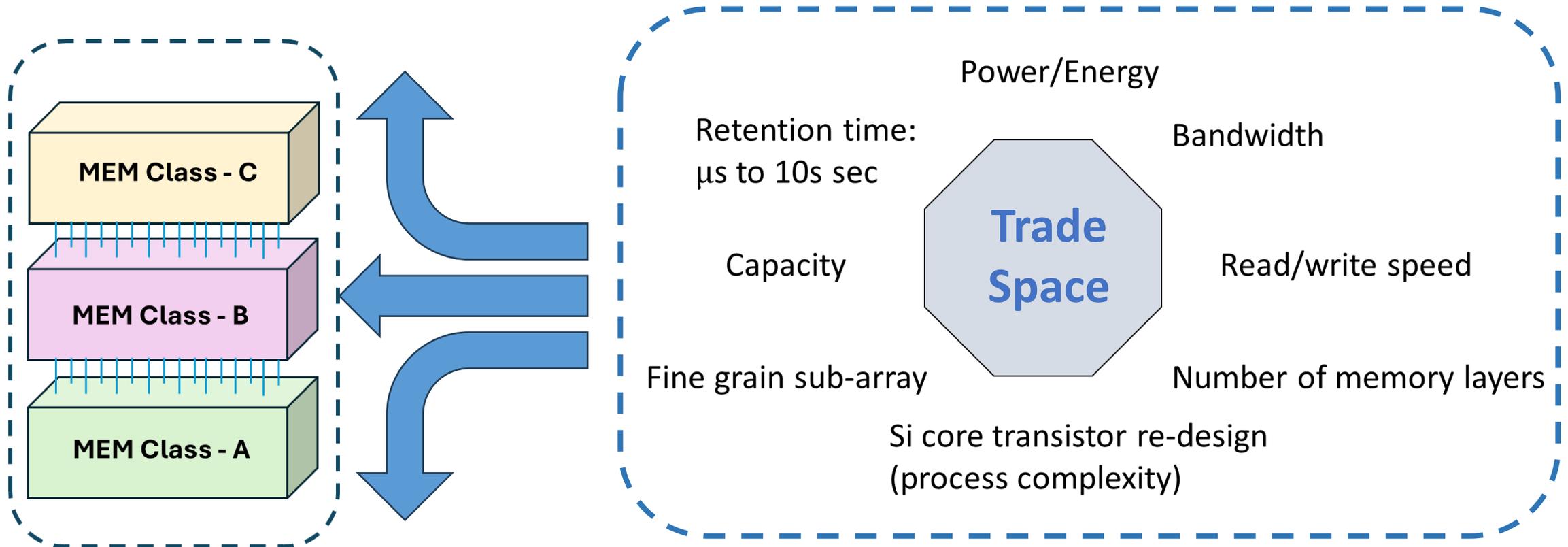
Oxide Semiconductor Gain Cell



Hybrid Gain Cell – High-density Scalable to N5

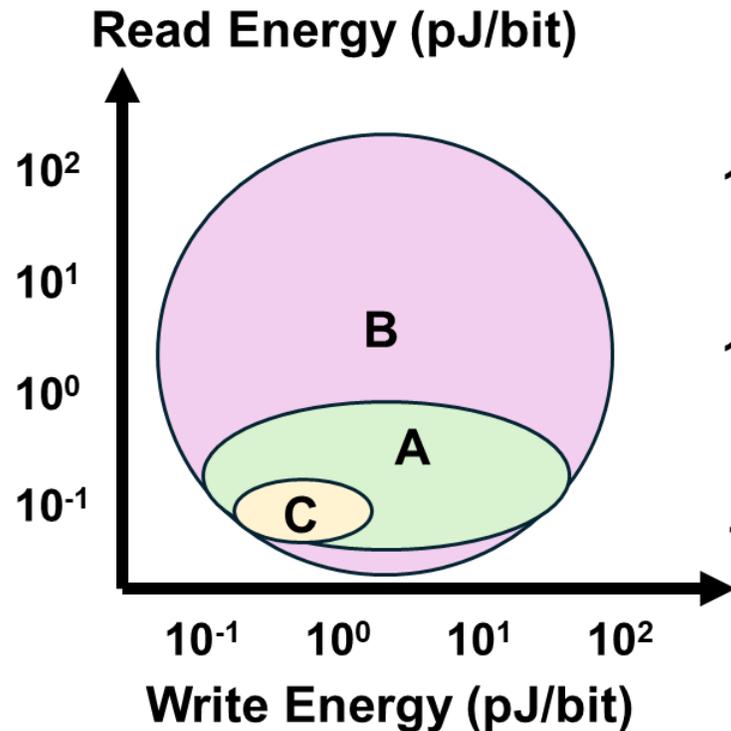


Optimize Tradeoff Guided by Software Use

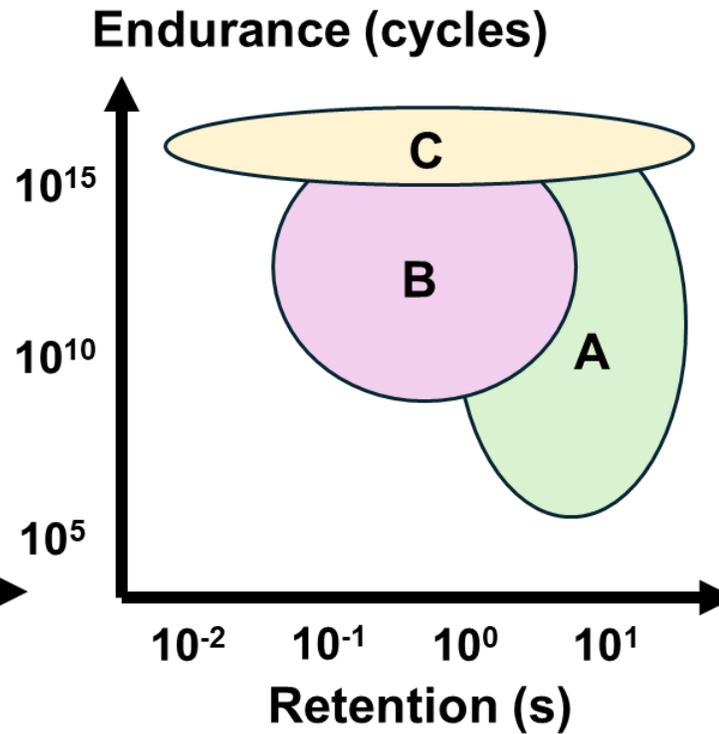


Diverse Hardware Specs for Software Data Types A, B, C

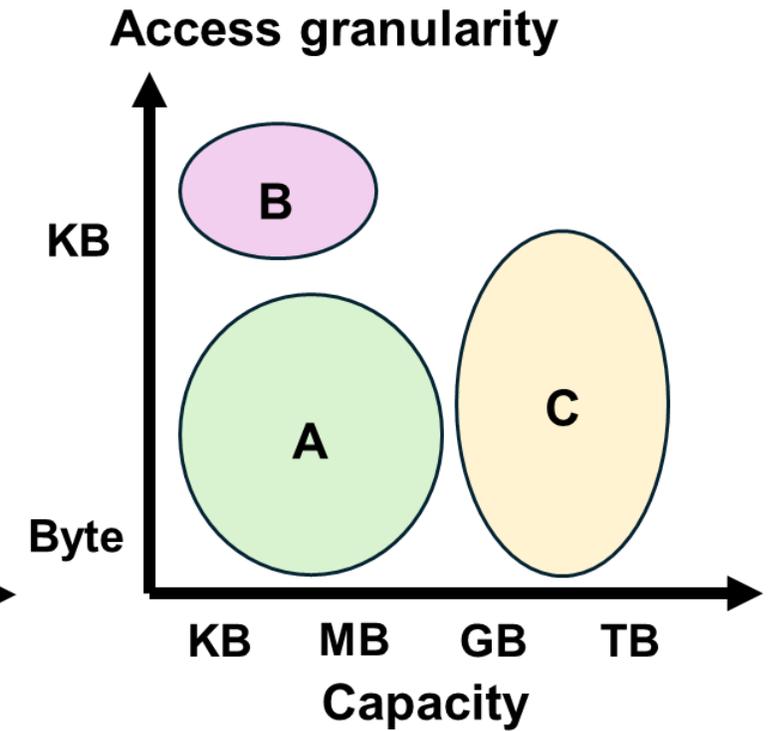
Subset



Intersection



Disjoint



Typical Memory Comparison



- Attributes in isolation
- Not application-correlated

	SRAM	DRAM	RRAM	MRAM
Energy	Low	Medium	High	High
Speed	High	Medium	Low	Low
Density	Low	Medium	High	High
Endurance	High	High	Low	Medium

We may be working too hard for no good reason !

Memory Comparison w/ Improvement Target

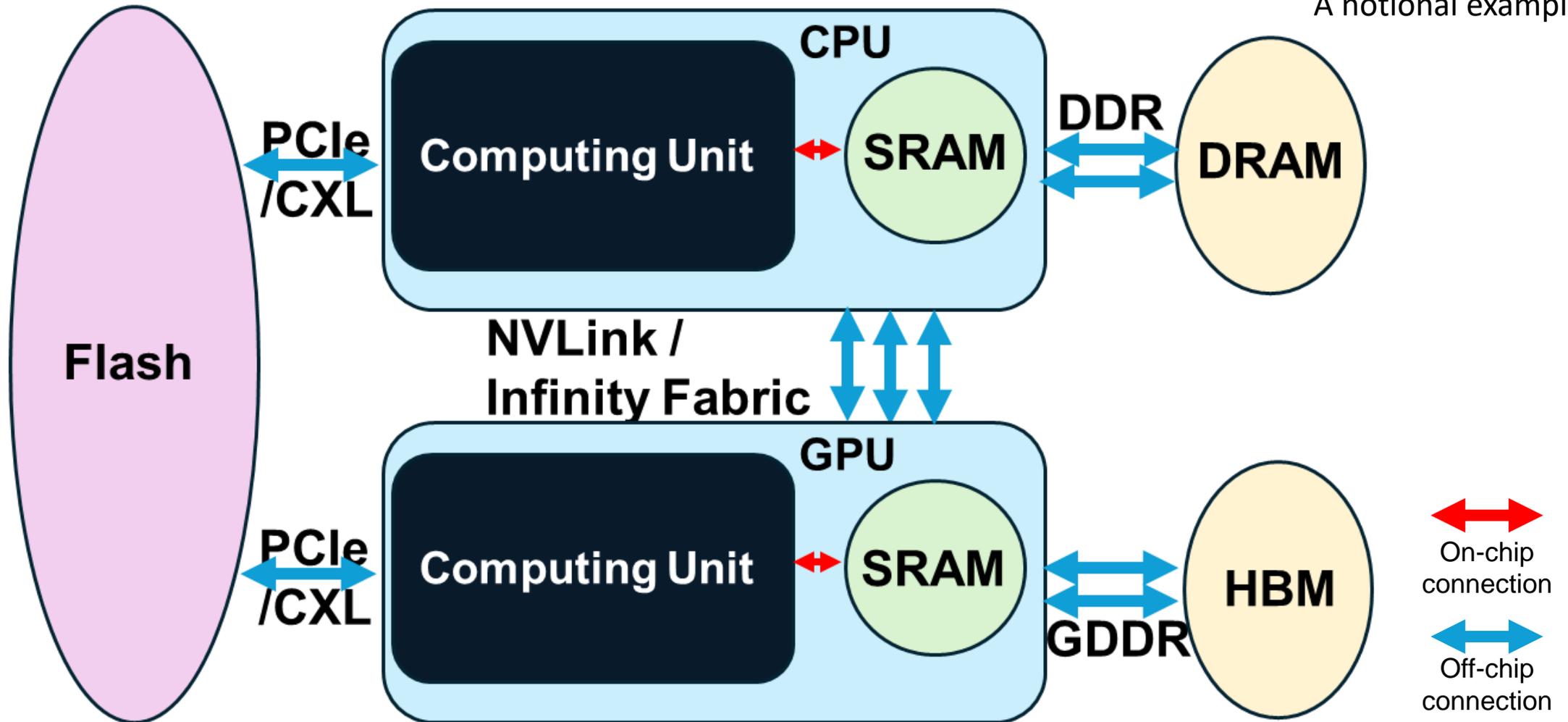
Improvements needed for each **memory** technology to be used in the **software** use cases, based on state-of-the-art macro demonstrations.

Data Type	SRAM	3D V-Cache	DRAM	OS-OS Gain Cell	Hybrid Gain Cell	RRAM	MRAM	PCM	FeRAM
B	Density	Standby power	Retention	Capacity	Capacity	Endurance & write energy	Write energy	Endurance & write energy	Read energy

Type B “streaming data” – e.g. streaming I/O, AI/ML activations, and data analytics

Physical Layers with Interface Protocol (Today)

A notional example



The KEY is INTEGRATION

160

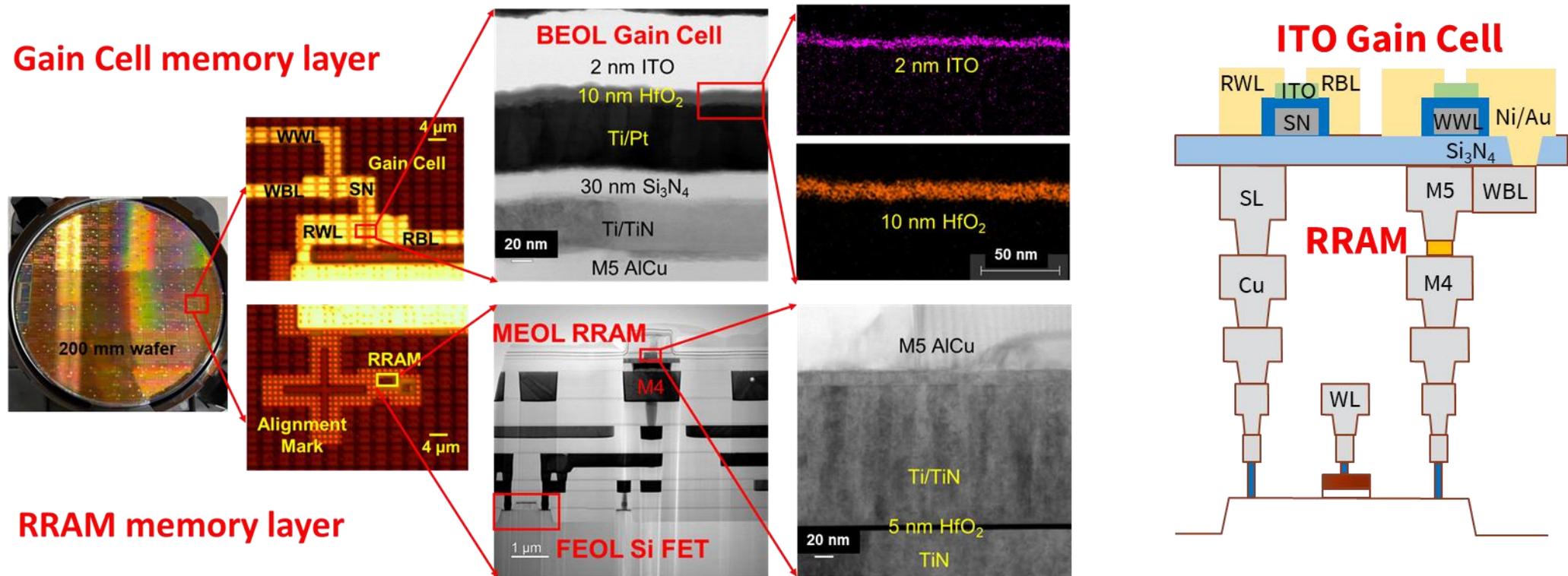
IEEE TRANSACTIONS ON MATERIALS FOR ELECTRON DEVICES, VOL. 1, 2024



Devices, Materials, Process Technologies, and Microelectronic Ecosystem Beyond the Exit of the Device Miniaturization Tunnel

H.-S. Philip Wong , *Life Fellow, IEEE*, and Subhasish Mitra , *Fellow, IEEE*

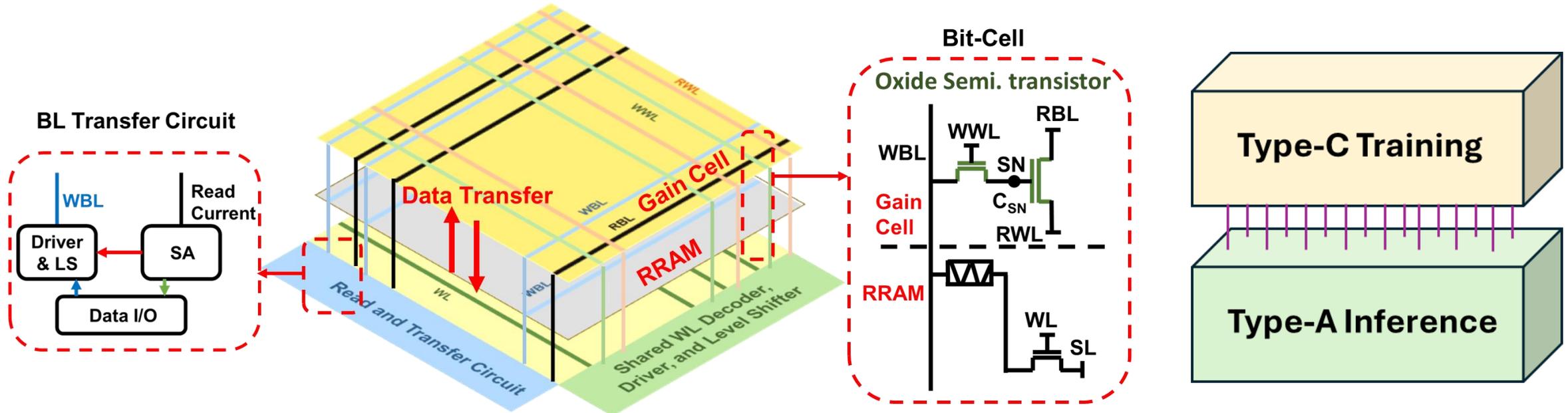
RRAM & Gain Cell Integration on Si CMOS: On-Chip Physical Integration



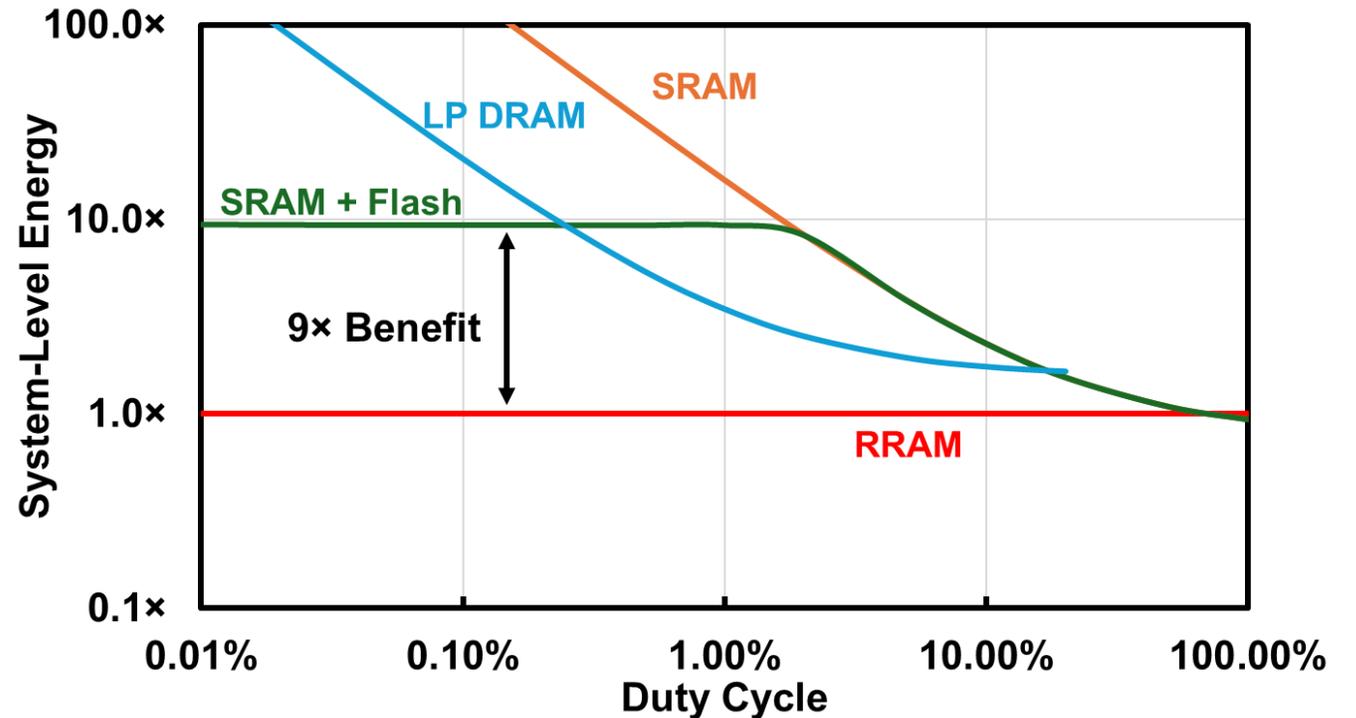
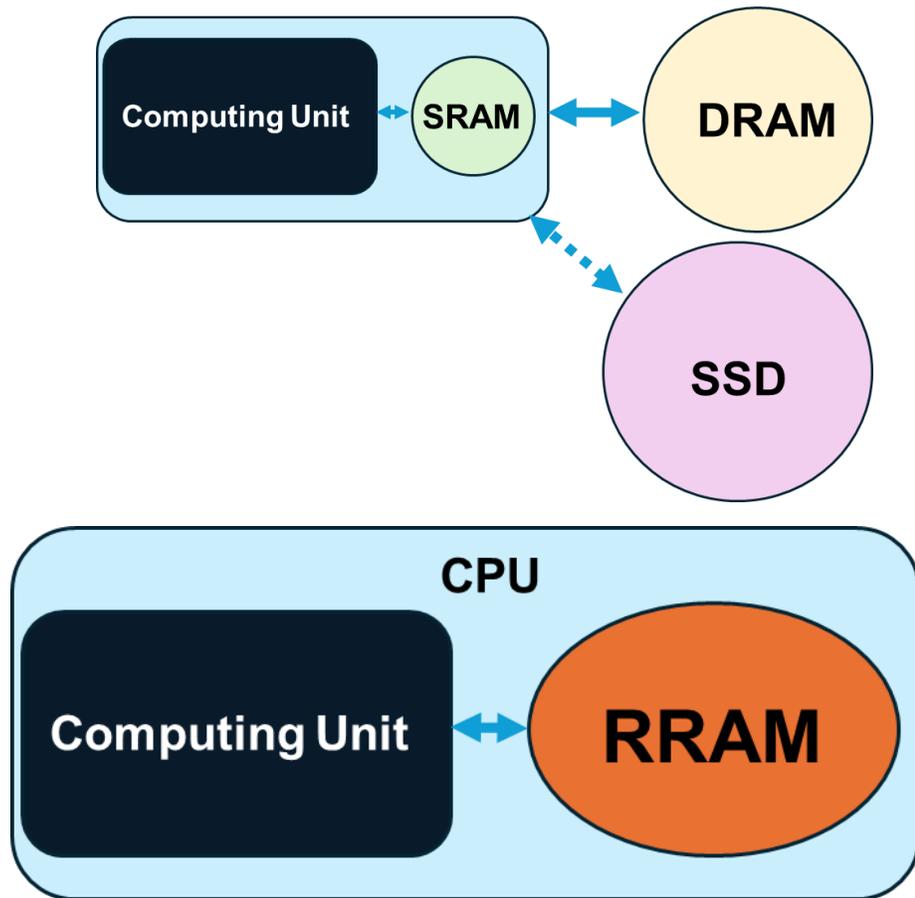
Shuhan Liu, ..., H.-S. Philip Wong, IEDM 2024, paper 15-3

RRAM & Gain Cell Integration on Si CMOS: On-Chip Architectural Integration

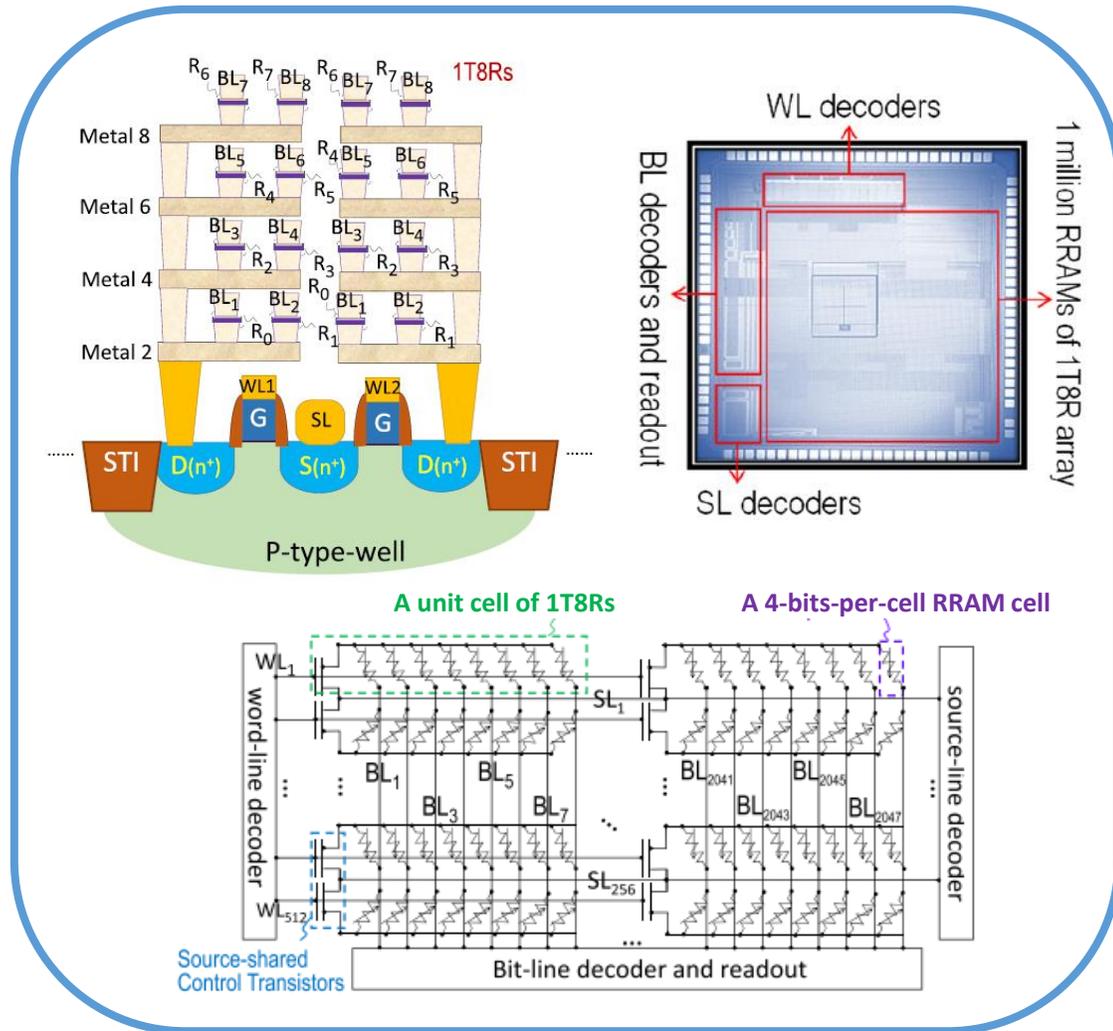
RRAM-Gain Cell Joint Memory Macro



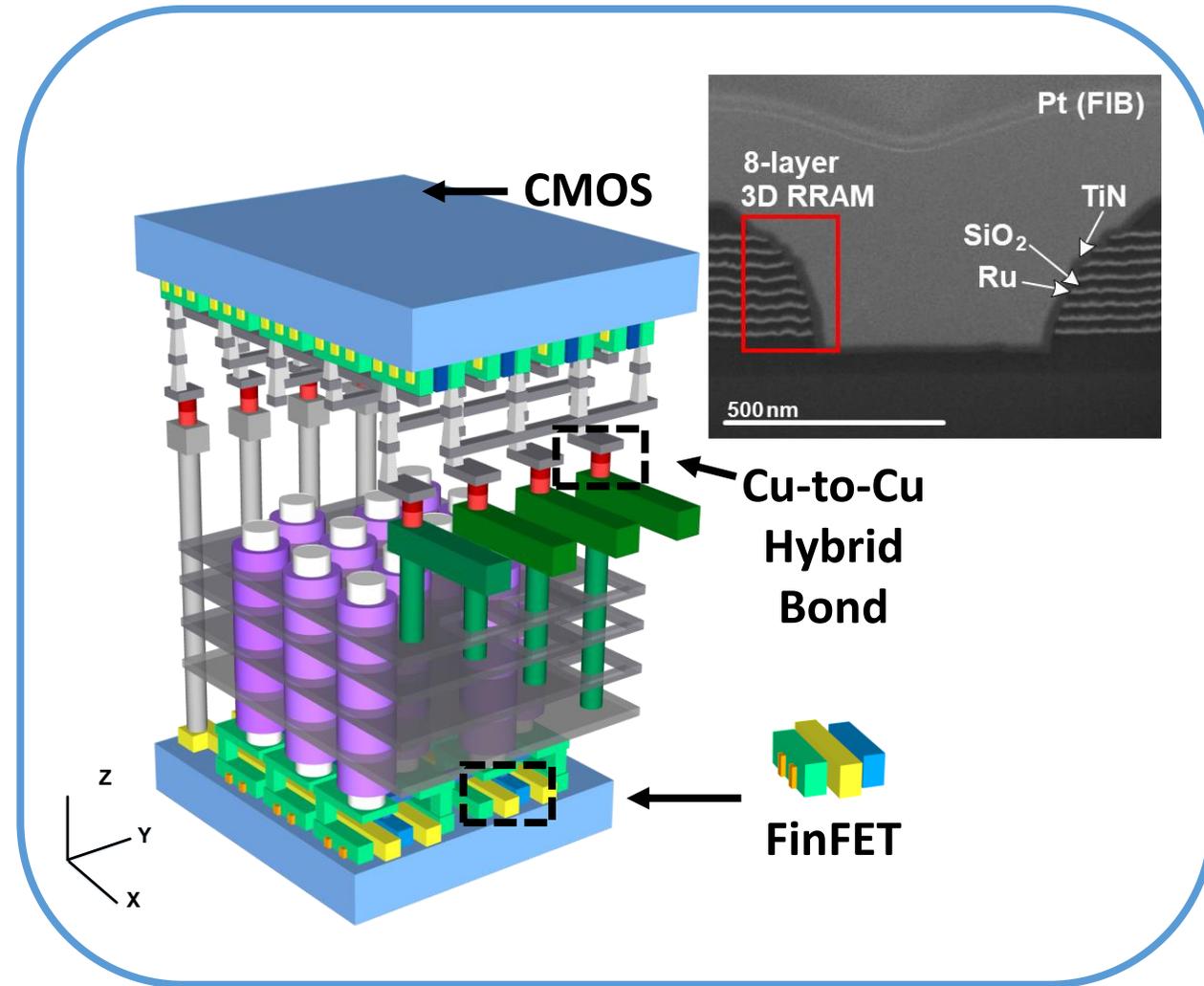
RRAM non-volatility provides 9x System energy benefits



High-Capacity RRAM: 1T8R, 3D RRAM

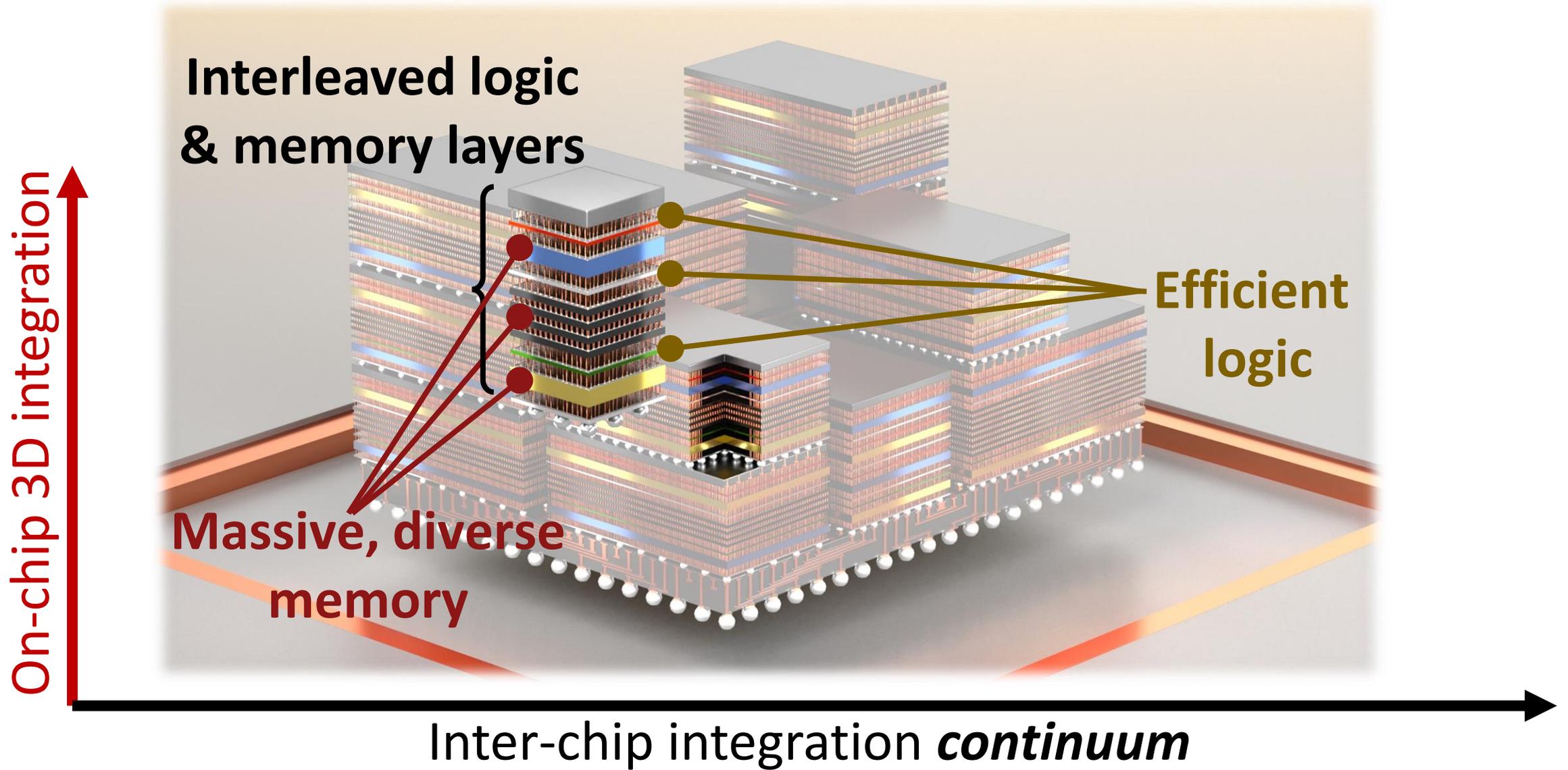


E. R. Hsieh, ..., S. Mitra, S. Wong, 2021 EDL.

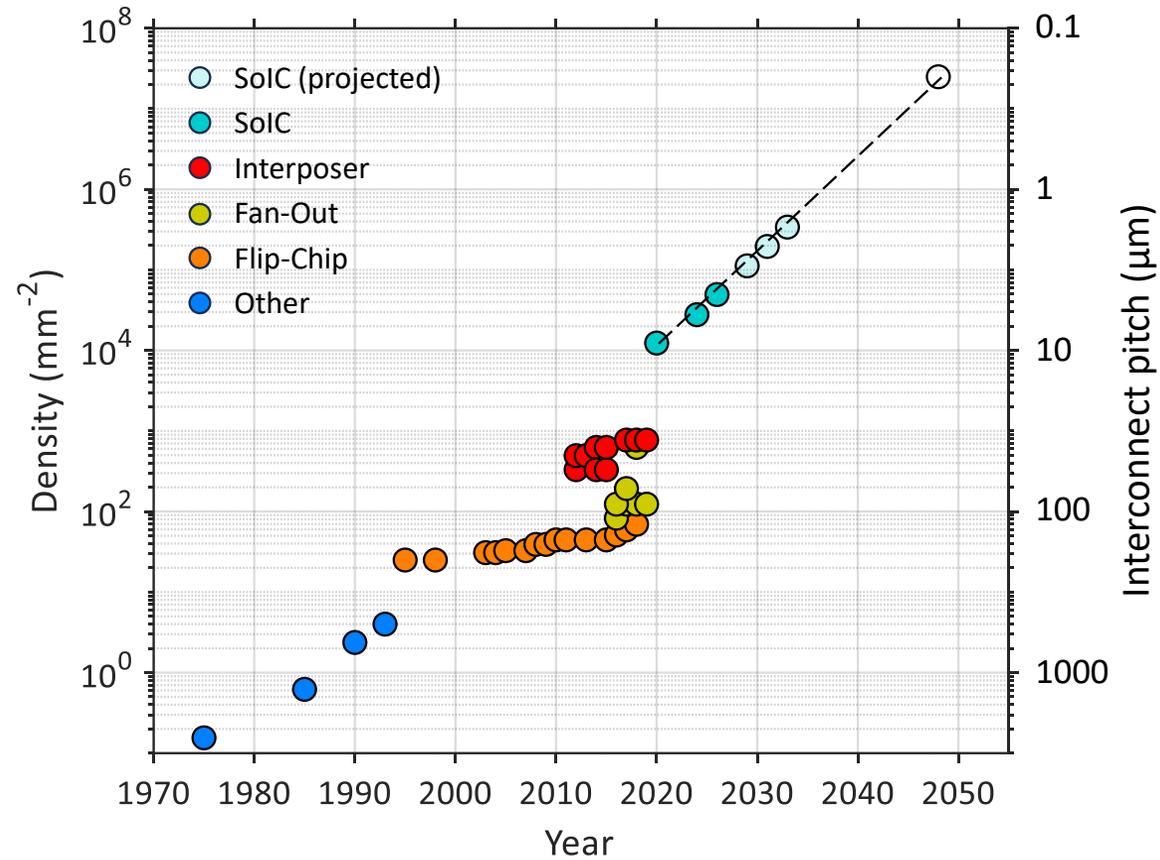


S. Qin, ..., H.-S. P. Wong, VLSI 2022, paper T04-3.

Continuum of Interconnection Density

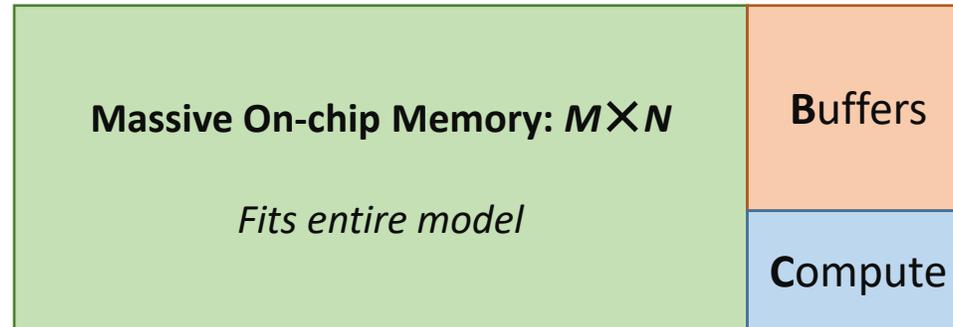


Interconnect Density – Inter-Chip Physical Integration



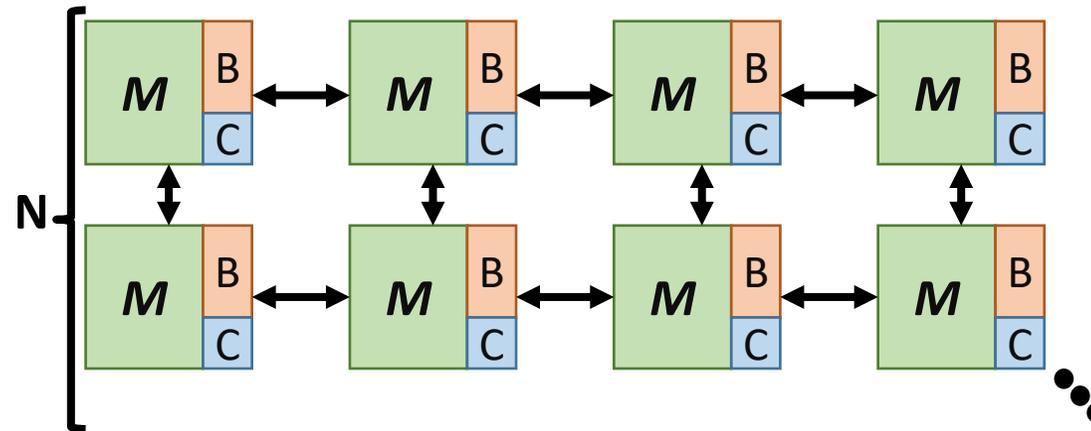
Illusion System – Inter-Chip Architectural Integration

Dream Chip:



\approx

Illusion System:



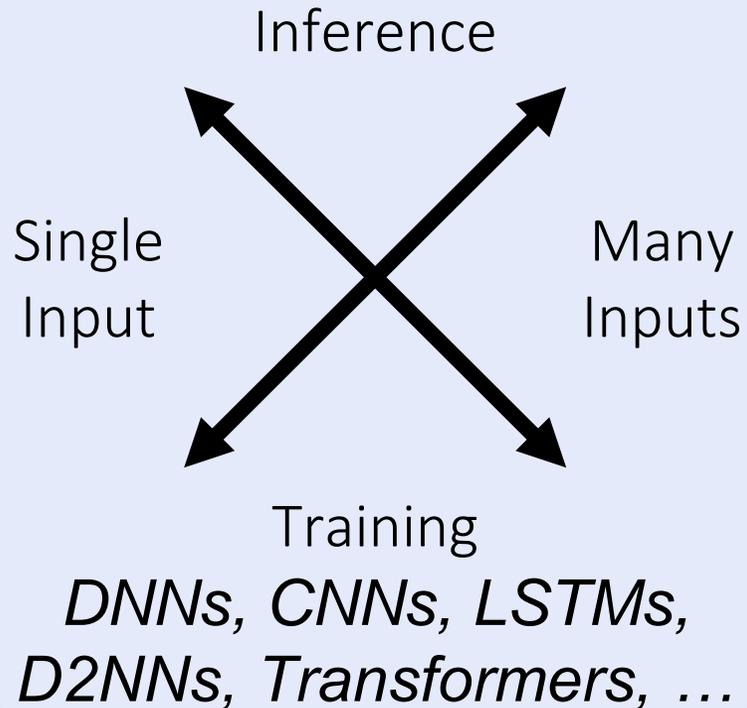
N: chips
M: memory
B: buffer
C: compute

Three Key Ideas: **Enough** on-chip memory + **Quick** chip ON/OFF + **Special** mapping

R.M. Radway, ... Subhasish Mitra, IEDM 2021, paper 25.4
and Nature Electronics 2021.

Illusion within $1.15 \times$ Dream EDP

Edge AI/ML Applications



Illusion \approx Dream $1.15 \times$ Dream EDP

Illusion Energy

$\leq 1.1 \times$

Dream Energy

Illusion Exec. Time

$\leq 1.05 \times$

Dream Exec. Time

(measured for AI inference)

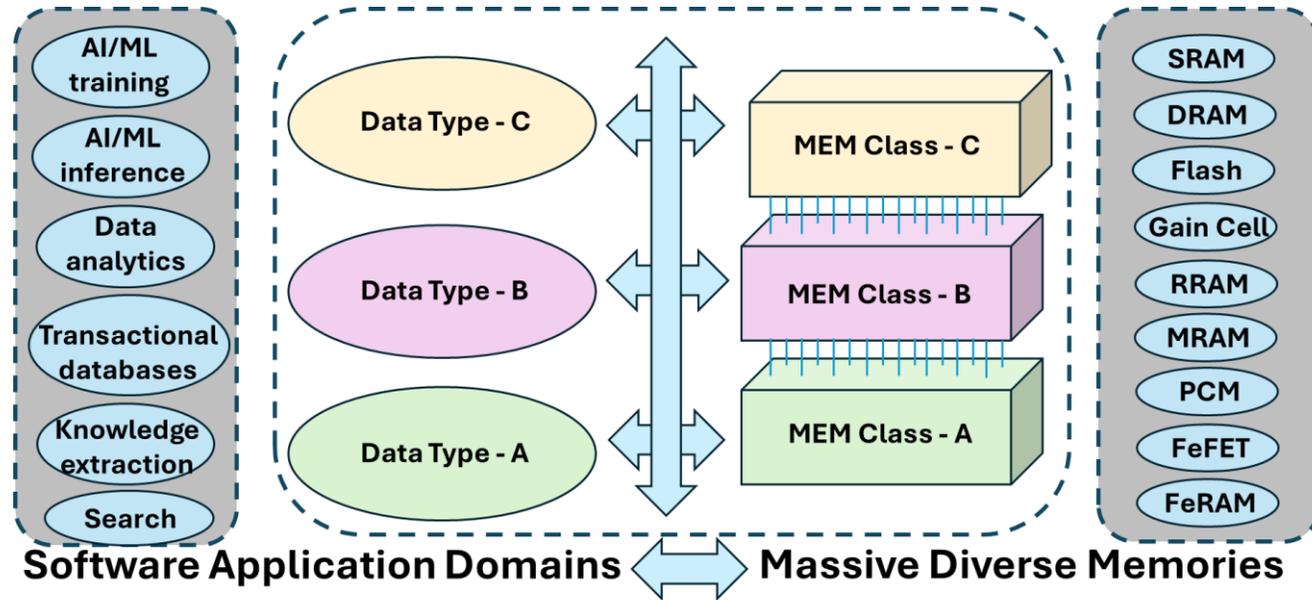
Hardware-proven *backed by theory*



6 to 8 Chip Illusions
32 KB to 96 MB Systems

Future of Memory: **Massive, Diverse, Tightly Integrated** with Compute – from Device to Software

- **Massive** High-Density On-Chip Memory
- **Diverse** Memories Exposed to Software
- **Tight Integration** with Compute Physically and Architecturally



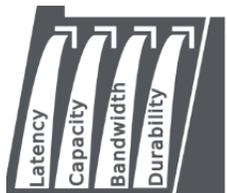
Acknowledgments



Semiconductor
Research
Corporation



ERI – 3DSoC



DAM

Stanford Differentiated Access Memories Project



Stanford University

Stanford | NMTRI
NON-VOLATILE MEMORY TECHNOLOGY RESEARCH INITIATIVE

Continuum of Interconnection Density

